



FORM PTO-1449	APPLICATION NO. 10/549,438	ATTORNEY DOCKET NO. 12939/003
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	FILING DATE June 5, 2006	GROUP ART UNIT 2811
(use several sheets if necessary)	FIRST NAMED INVENTOR: Mike Kunze et al.	
	EXAMINER NAME: Unknown	

EXAMINER INITIALS	Cite No.	DOCUMENT NUMBER Number-Kind Code (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where, Relevant Passages or Relevant Figures Appear
	A1	6,647,796 B2	11/18/2003	Beach et al.	
	A2	7,007,551 B2	03/07/2006	Zdeblick et al.	
	A3	7,013,734 B2	03/21/2006	Zdeblick et al.	
	A4	7,028,550 B2	04/18/2006	Zdeblick et al.	
	A5	7,066,031 B2	06/27/2006	Zdeblick et al.	
	A6	7,073,387 B2	07/11/2006	Zdeblick et al.	
	A7	7,086,288 B2	08/08/2006	Lee et al.	
	A8	7,181,972 B2	02/27/2007	Dasgupta et al.	
	A9	7,189,358 B2	03/13/2007	Beach et al.	
	A10	2002/0066319 A1	06/06/2002	Beach et al.	
	A11				
	A12				
	A13				

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER Number-Kind Code (if known)	DATE	COUNTRY	CLASS/ SUBCLASS	TRANSLATION YES OR NO
	A14					
	A15					
	A16					
	A17					

EXAMINER INITIAL	NON PATENT LITERATURE DOCUMENTS (Include name of author, title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date page(s), volume-issue number(s), publisher, city and/or country where published.					T
	A18	C. Youtsey, G. Bulman and I. Adesida, Dopant-Selective Photoenhanced Wet Etching of GaN, Journal of Electronic Materials, Vol. 27, No. 4, 1998, Microelectronics Laboratory and Department of Electrical and Computer Engineering, Univ. of Illinois, Urbana, IL 61801, CREE Research, Inc. Durham, NC 27713.				
	A19	Imaging Metallic Thin-Film Uniformity Using Nondestructive 1-20 GHz Magnetic Evanescent Microwave Probe, Electrical Engineering and Computer Science, Case Western Reserve University.				
	A20	C. Bieth et al., Recent Development in ECR Sources, Nukleonika 2003; 48 (Supplement 2); S93-S98.				
	A21					
	A22					

EXAMINER	DATE CONSIDERED
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.